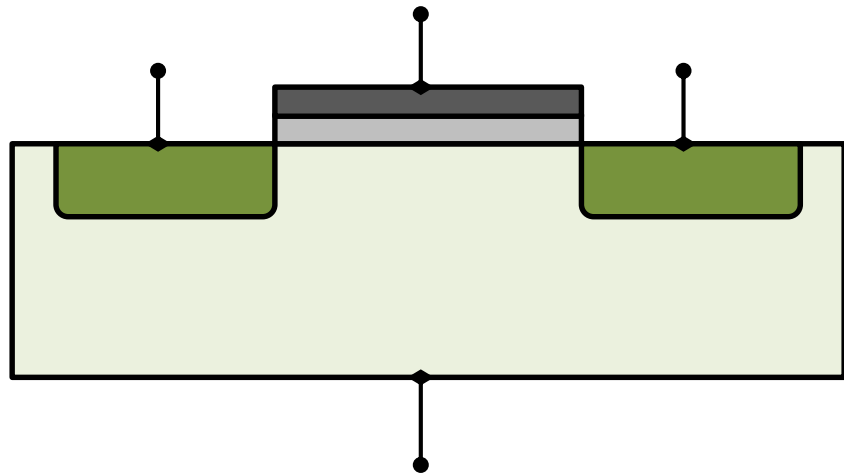


# MOSFET → Chapter 5

- MOS – Metal Oxide Semiconductor
- FET – Field-Effect Transistor
- 4 terminal device

### Advantages:

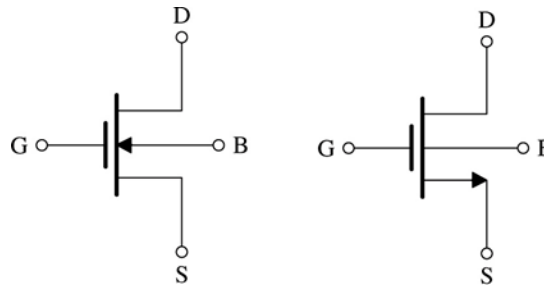
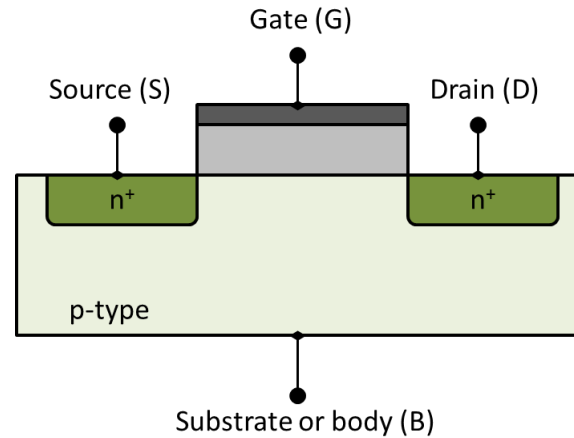
- Small area; comparatively
- Less power
- Relatively simple manufacturing process



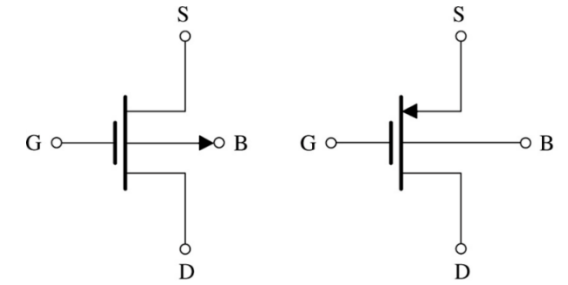
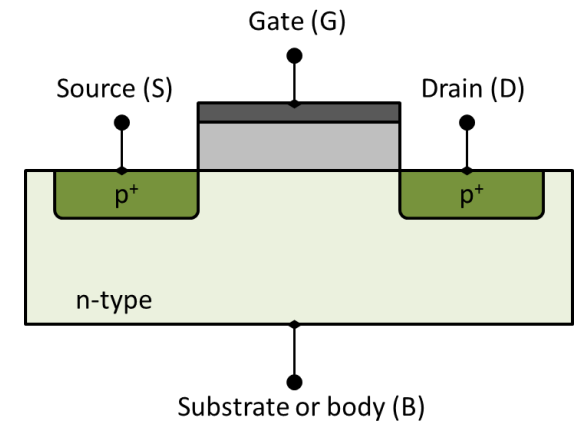
Cross Section Diagram

\* If the bulk terminal is omitted, it is presumed is connected to the source

### • nMOS Transistor



### • pMOS Transistor

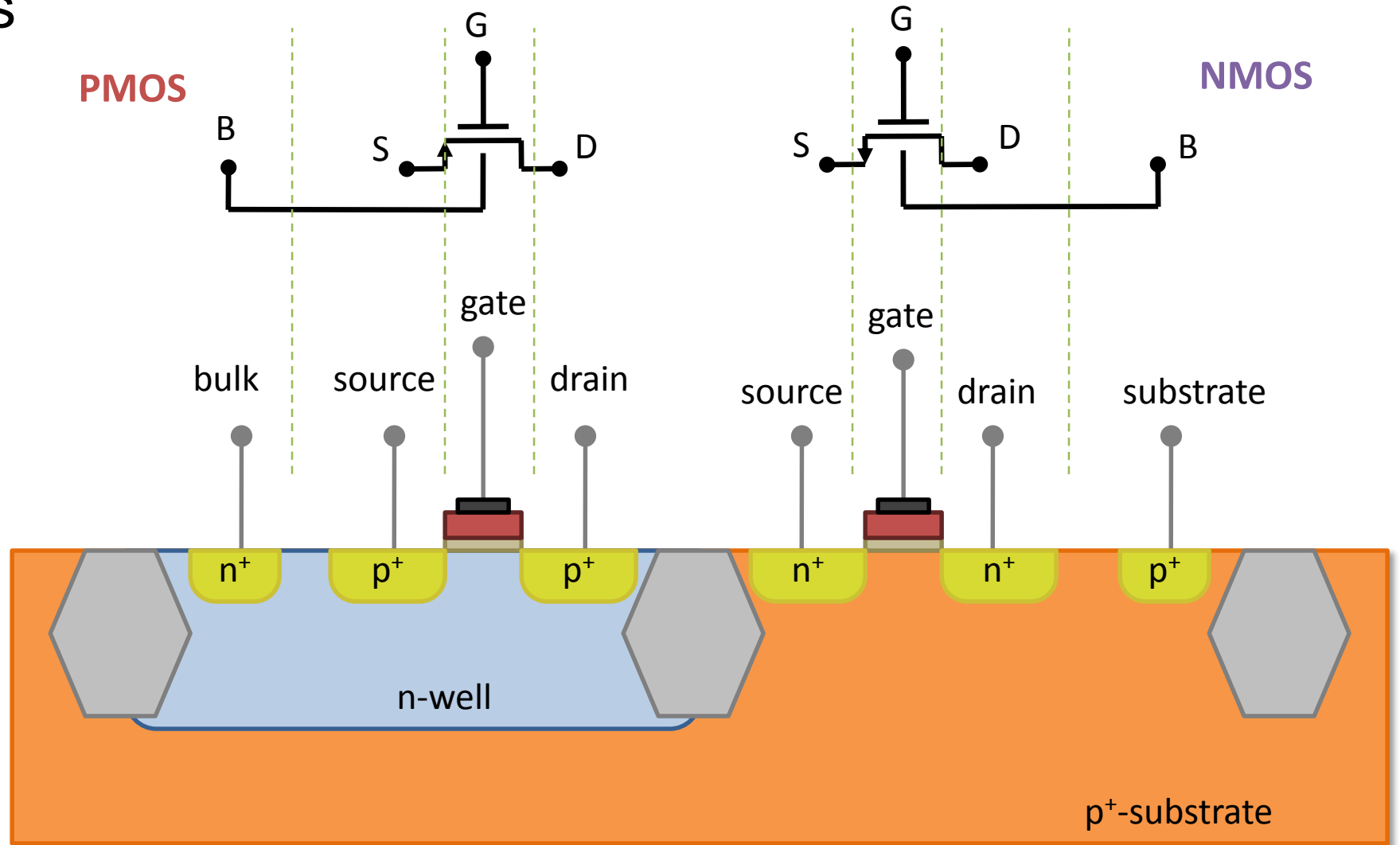


Symbol

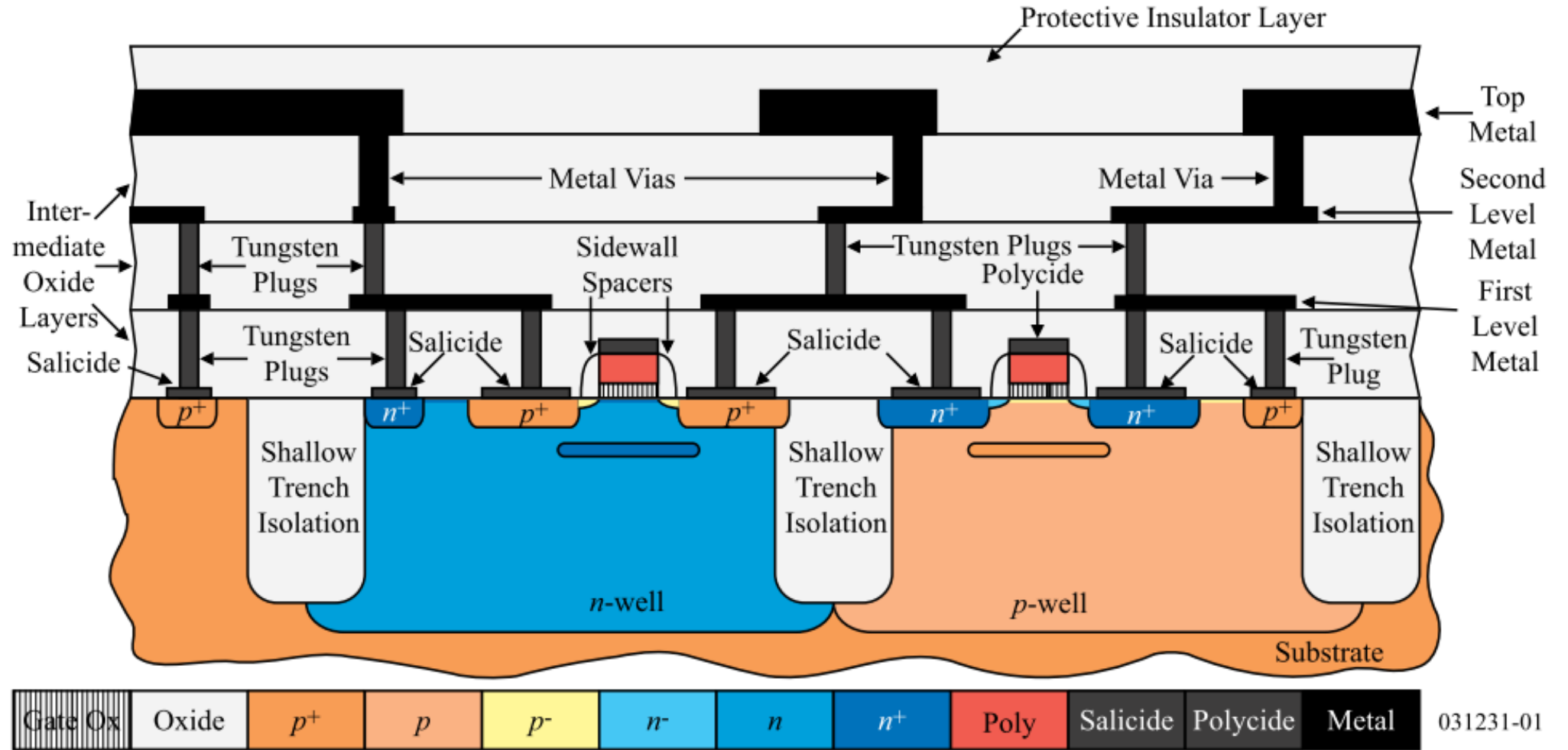
# CMOS Transistors



Complementary MOS



# Modern CMOS Technology



# nMOS Operation

- Two external voltage sources are required for biasing
- Three operation modes:

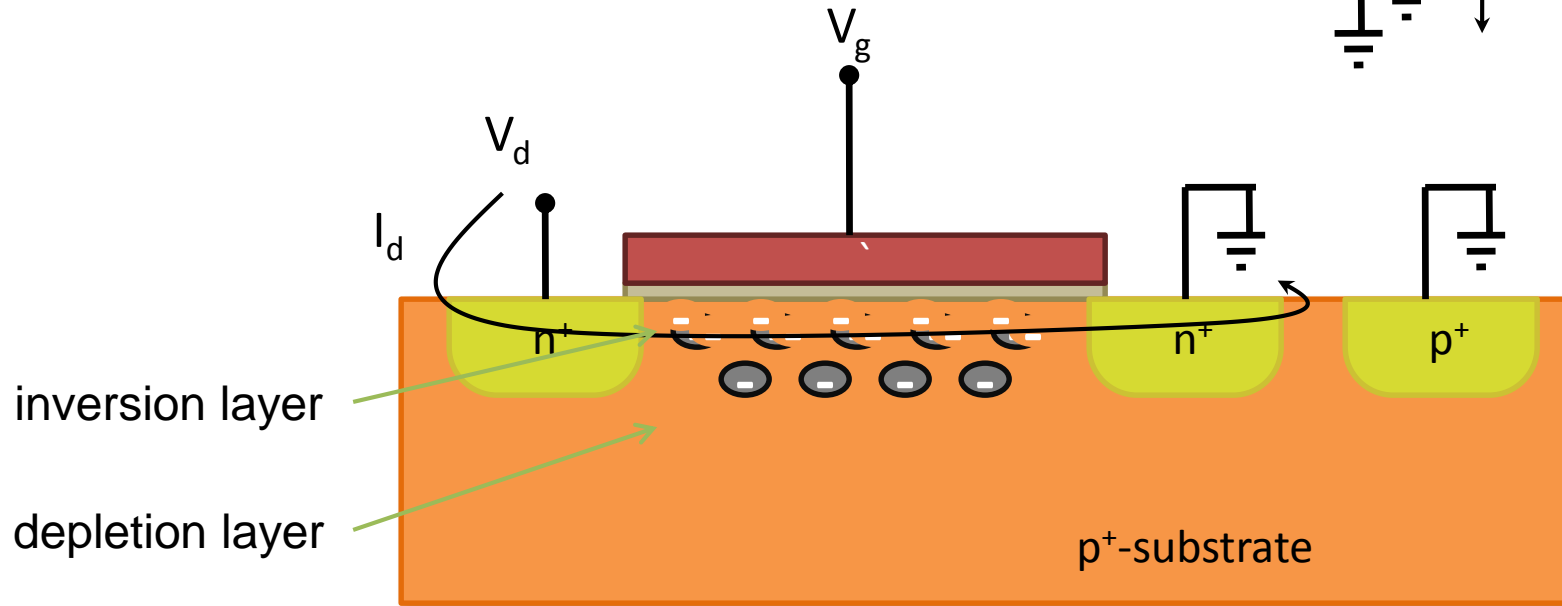
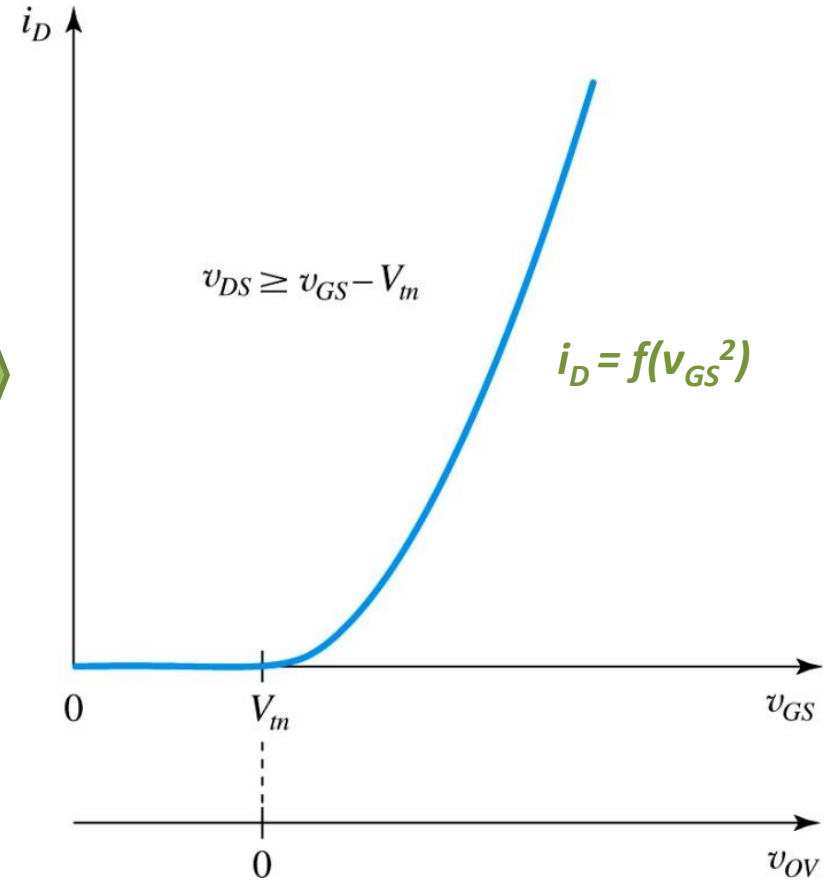
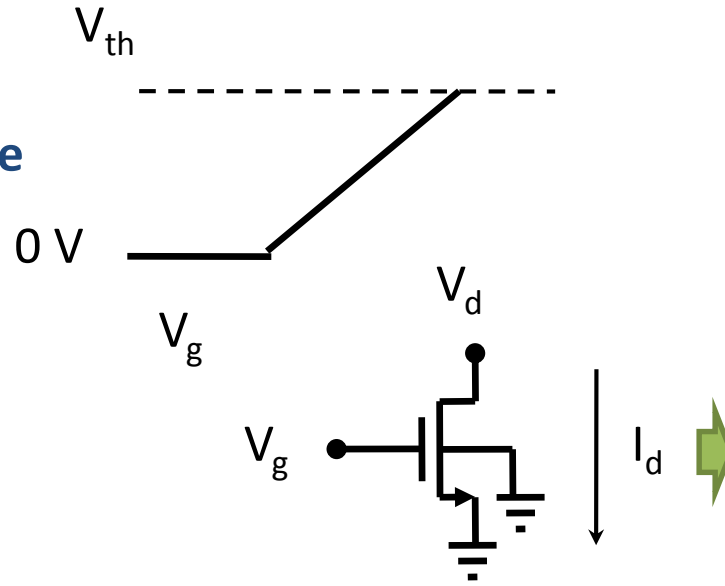
1) Cut-Off

*used for switching!*

2) Ohmic

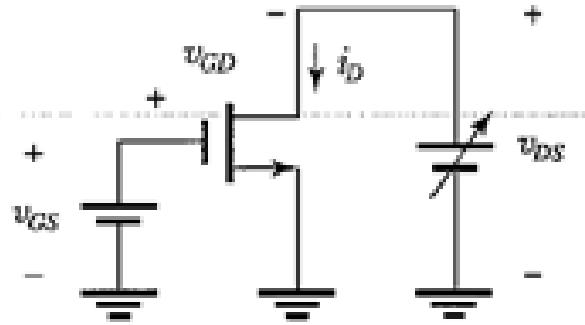
3) Saturation

*used for amplification!*



# nMOS Operation → Saturation

- $V_{GS} > V_{th}$
- $V_{DS} > V_{GS} - V_{th} = V_{ov}$
- $i_G = 0$



Channel Length Modulation Parameter [1/V]

$$I_D = \frac{1}{2} K_n \frac{W}{L} (V_{GS} - V_{th})^2 (1 + \lambda V_{DS})$$

$$\approx \frac{1}{2} k_n' \frac{W}{L} (V_{GS} - V_{th})^2$$

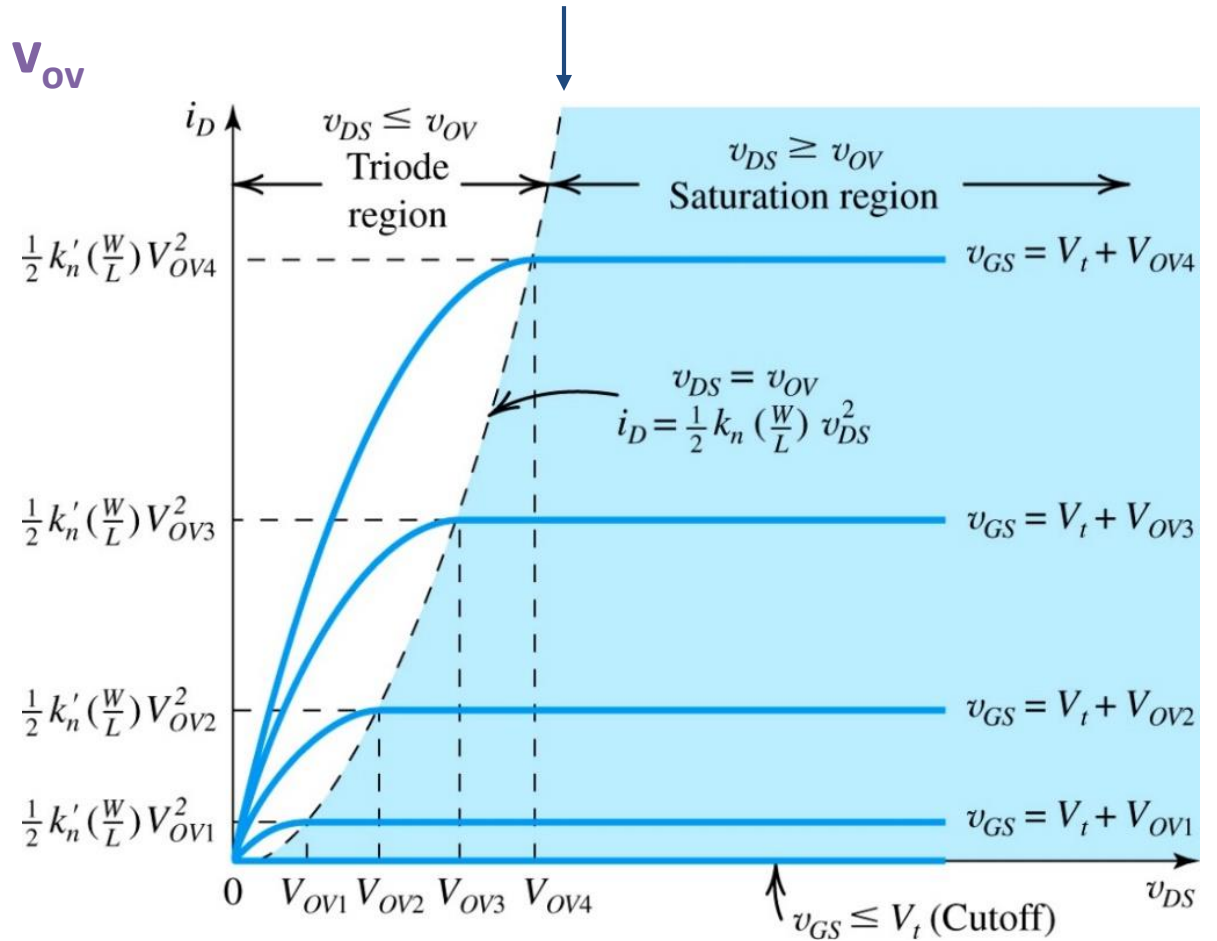
Transconductance Parameter [A/V<sup>2</sup>]

$$k_n' = \mu_n C_{ox}$$

Over-drive Voltage

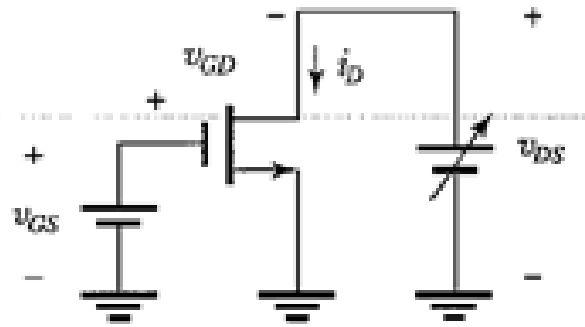
$$V_{ov} = V_{GS} - V_{th}$$

$$i_D = f(v_{GS}, v_{DS})$$



# nMOS Operation → Ohmic

- $V_{GS} > V_{th}$
- $V_{DS} < V_{GS} - V_{th} = V_{ov}$
- $i_G = 0$



$$I_D = k_n' \frac{W}{L} \left[ (V_{GS} - V_{th})(V_{DS}) - \frac{1}{2} V_{DS}^2 \right]$$

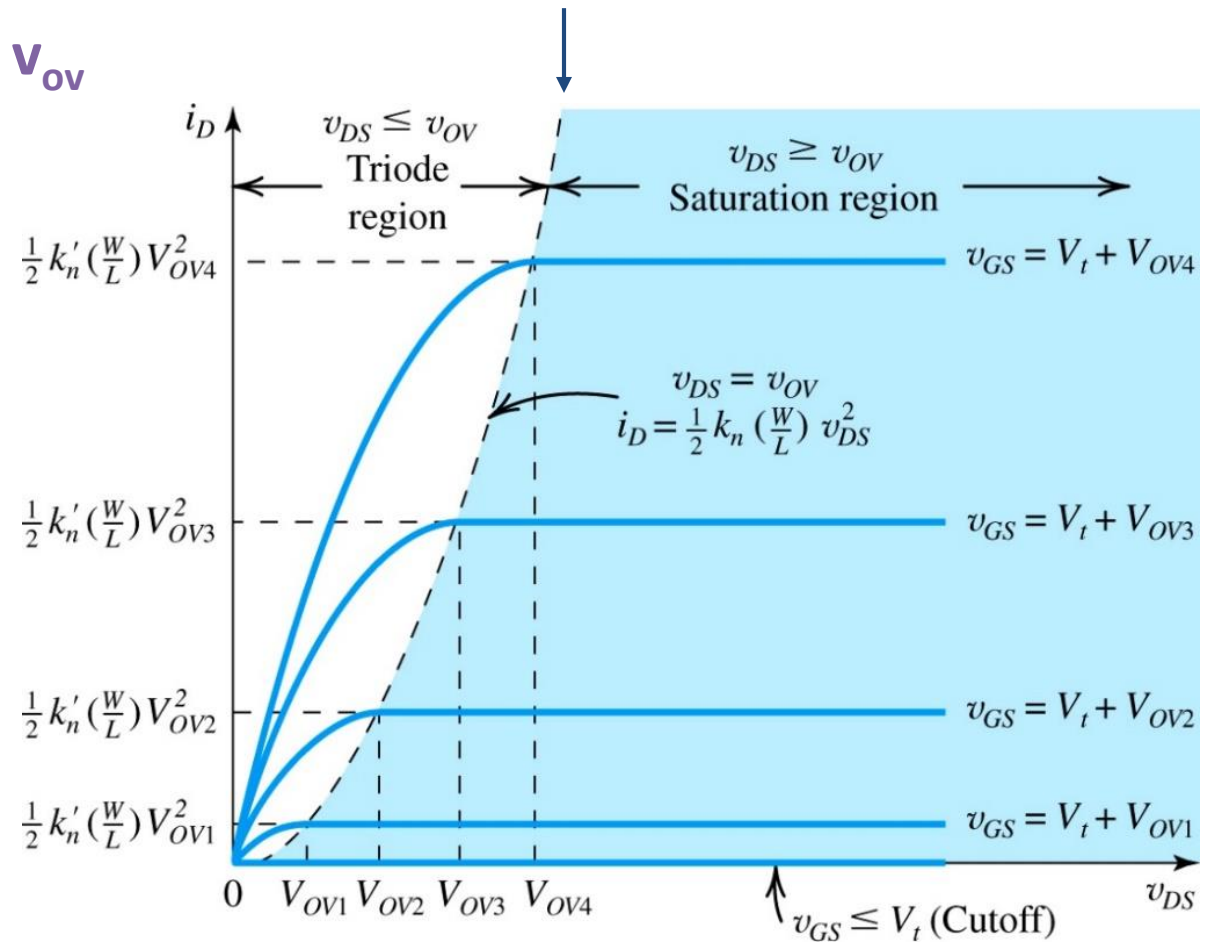
$$\approx k_n' \frac{W}{L} (V_{GS} - V_{th}) \cdot V_{DS}$$

$$r_{ds} = \frac{1}{k_n' \frac{W}{L} (V_{GS} - V_{th})}$$

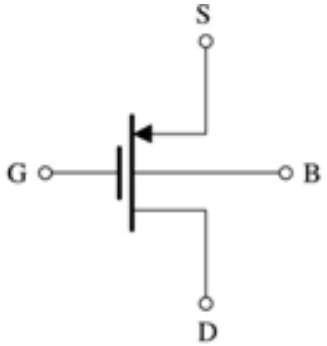
## Over-drive Voltage

$$V_{ov} = V_{GS} - V_{th}$$

$$i_D = f(v_{GS}, v_{DS})$$



# Large Signal Model (pMOS)



## → Saturation Mode

- $v_{SG} > |v_{th}|$
- $v_{SD} > v_{SG} - |v_{th}| = v_{ov}$
- $i_G = 0$

$$I_D = \frac{1}{2} k_n' \frac{W}{L} (V_{SG} - |V_{th}|)^2 (1 + \lambda V_{SD})$$

$$\approx \frac{1}{2} k_n' \frac{W}{L} (V_{SG} - |V_{th}|)^2$$

## → Ohmic Mode

- $v_{SG} > |v_{th}|$
- $v_{SD} < v_{SG} - |v_{th}| = v_{ov}$
- $i_G = 0$

$$I_D = k_n' \frac{W}{L} \left[ (V_{SG} - |V_{th}|)(V_{SD}) - \frac{1}{2} V_{SD}^2 \right]$$

$$\approx k_n' \frac{W}{L} (V_{SG} - |V_{th}|) \cdot V_{SD}$$

## Example 5.2

Consider an nMOS transistor fabricated in a  $0.18\mu\text{m}$  process with  $L=0.18\mu\text{m}$  and  $W=2\mu\text{m}$ . The process technology is specified to have  $C_{\text{ox}}=8.6\text{fF}/\mu\text{m}^2$ ,  $\mu_n=450\text{cm}^2/\text{V}\cdot\text{s}$ , and  $V_{\text{th}}=0.5\text{V}$ .

- Find  $V_{\text{GS}}$  and  $V_{\text{DS}}$  that result in the MOSFET operating at the edge of saturation with  $I_{\text{D}}=100\ \mu\text{A}$ .
- If  $V_{\text{GS}}$  is kept constant, find  $V_{\text{DS}}$  that results in  $I_{\text{D}}=50\mu\text{A}$ .
- To investigate the use of the MOSFET as a linear amplifier, let it be operating in saturation with  $V_{\text{DS}}=0.3\text{V}$ . Find the change in  $i_{\text{D}}$  resulting from  $v_{\text{GS}}$  changing from  $0.7\text{V}$  by  $+0.01\text{V}$  and by  $-0.01\text{V}$ .